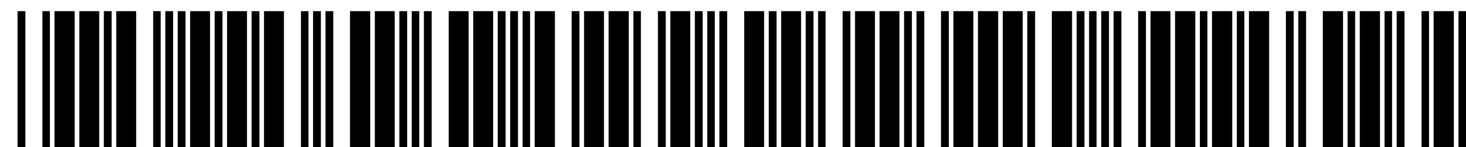

(12) **United States Design Patent**
Nasu

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(45) **Date of Patent: ** May 7, 2019**

(54) **PROBE PIN**

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(**) Term: **15 Years**

(21) Appl. No.: **29/615,737**

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(51) **LOC (11) Cl.** **13-03**

(52) **U.S. Cl.**
USPC **D13/154**

(58) **Field of Classification Search**
USPC D24/140, 107, 128, 133, 231, 232, 108, D24/112–114, 127, 129, 130, 146, 147, D24/186; D13/147, 154, 184, 199; D8/387, 388, 391
CPC . H01R 4/48; H01R 4/52; H01R 13/05; H01R 13/213; H01R 13/24; H01R 13/2421; H01R 13/2471; H01R 13/26; H01R 13/41; G01R 31/04; G01R 1/07314; G01R 1/06722; G01R 1/067; G01R 1/06733; G01R 1/07307; A61B 2017/00349
See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a probe pin, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a probe pin, showing the claimed design;
FIG. **2** is a front view of the probe pin;
FIG. **3** is a rear view of the probe pin;
FIG. **4** is a left side view of the probe pin;
FIG. **5** is a right side view of the probe pin;
FIG. **6** is a top plan view of the probe pin;
FIG. **7** is a bottom plan view of the probe pin;
FIG. **8** is an enlarged left side view of the probe pin; and,
FIG. **9** is an enlarged view of the section of the probe pin as indicated in FIG. **2**.
The broken lines shown in the figures represent portions of the probe pin that form no part of the claimed design. The line-dot broken lines indicate boundary lines between the claimed portions and the disclaimed portions, and are for illustration only and form no part of the claimed design.

1 Claim, 3 Drawing Sheets

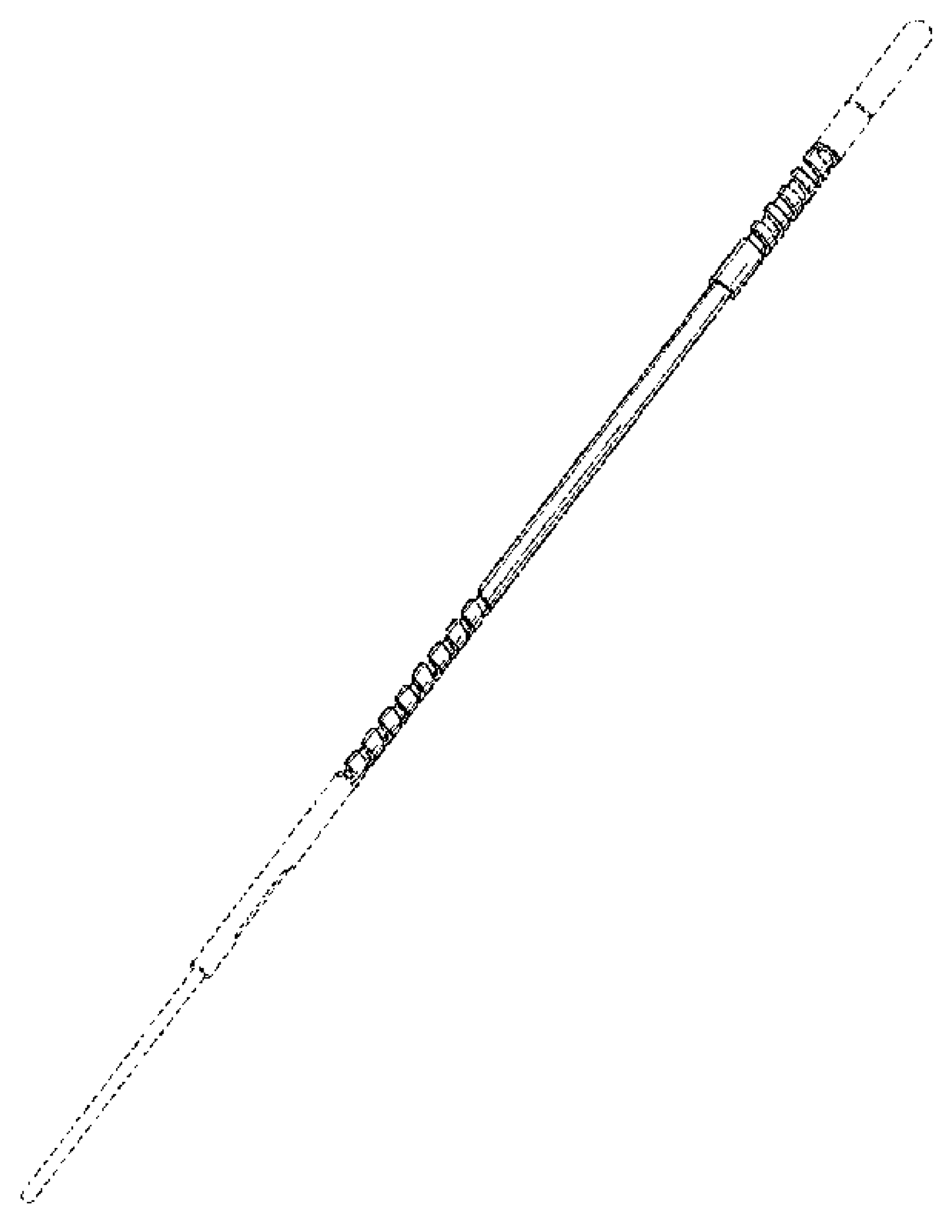

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Fig.1

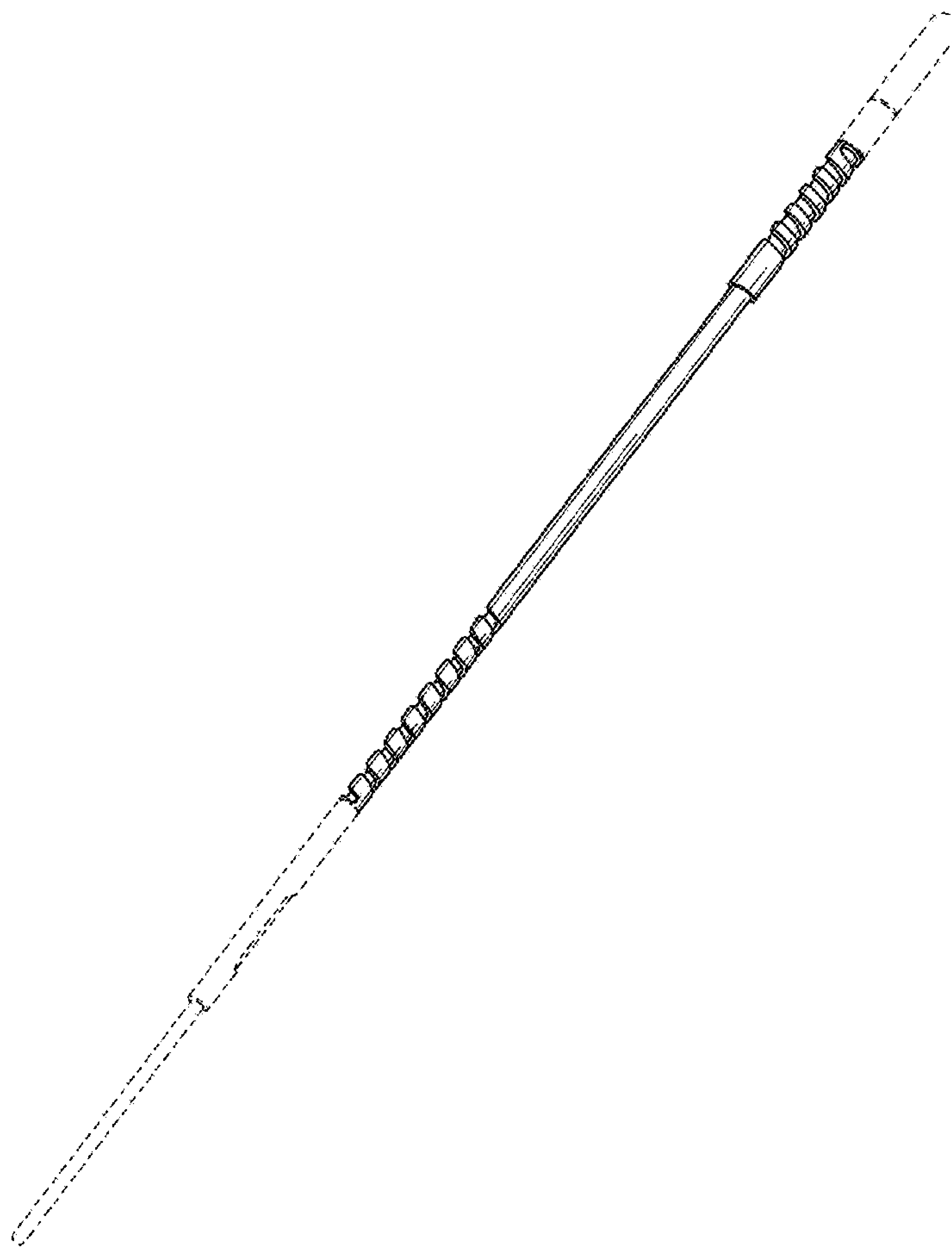

Fig.2

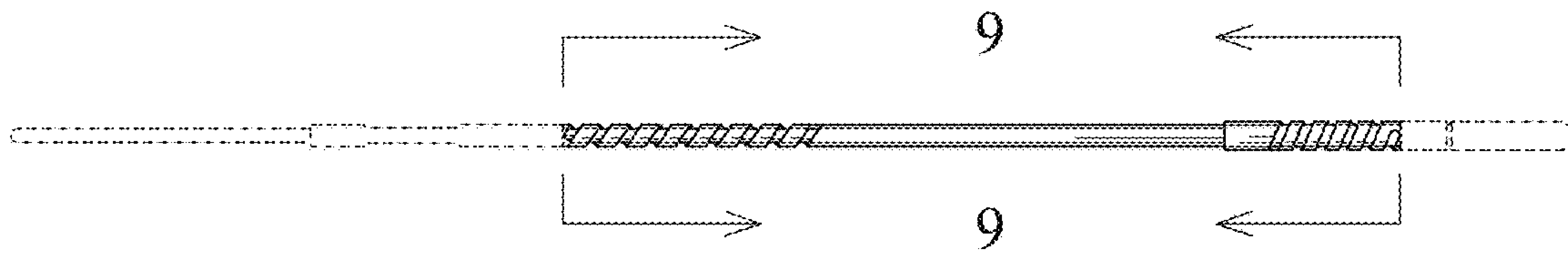

Fig.3

Fig.4

Fig.5

Fig.6

Fig.7

Fig.8

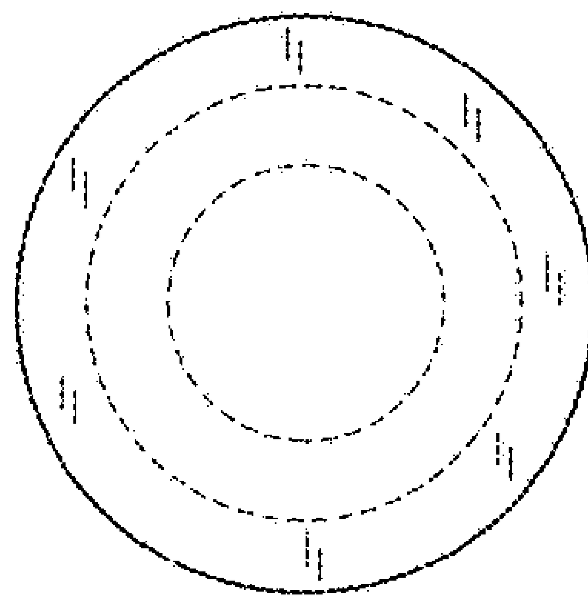

Fig.9